

More CMOS and some Bipolar

LECTURE 24

- revisiting the DRAM
- CMOS camera
- BJT logic
- ECL
- high-frequency performance comparison

Writing and Reading a ONE

WRITE:

Plate at $V_{DD}/2$

Drive BIT to V_{DD}

Raise V_{Word} to $V_{DD} + V_T$

What does V_S become?

What does V_{st} become?

READ:

Plate at $V_{DD}/2$

Pre-charge V_{Bit} to $V_{DD}/2$

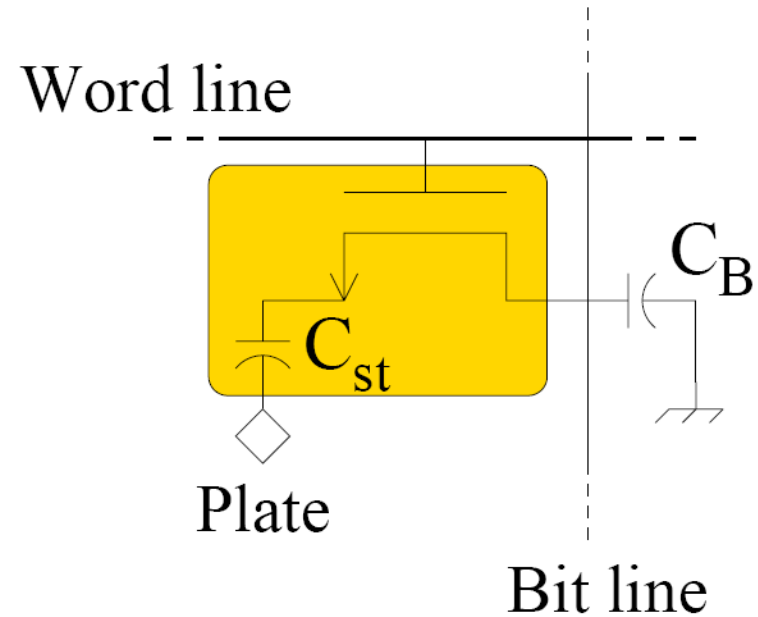
Float V_{Bit}

Enable word line

Sense V_{Bit}

What does V_{Bit} become?

Does V_S change?



Writing and Reading a ZERO

WRITE:

Plate at $V_{DD}/2$

Drive BIT to 0.

Enable word line ($V_{GS}=V_{DD}$).

What does V_S become?

What does V_{st} become?

READ:

Plate at $V_{DD}/2$

Pre-charge V_{Bit} to $V_{DD}/2$

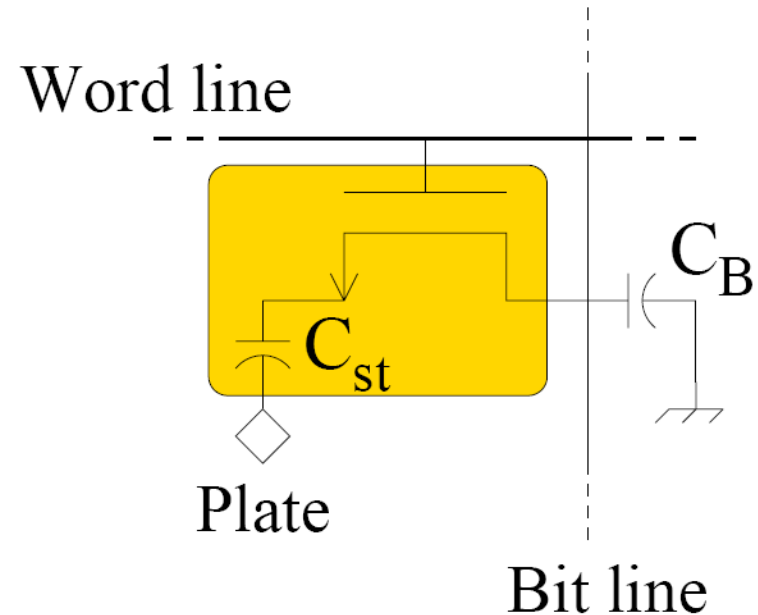
Float V_{Bit}

Enable word line

Sense V_{Bit}

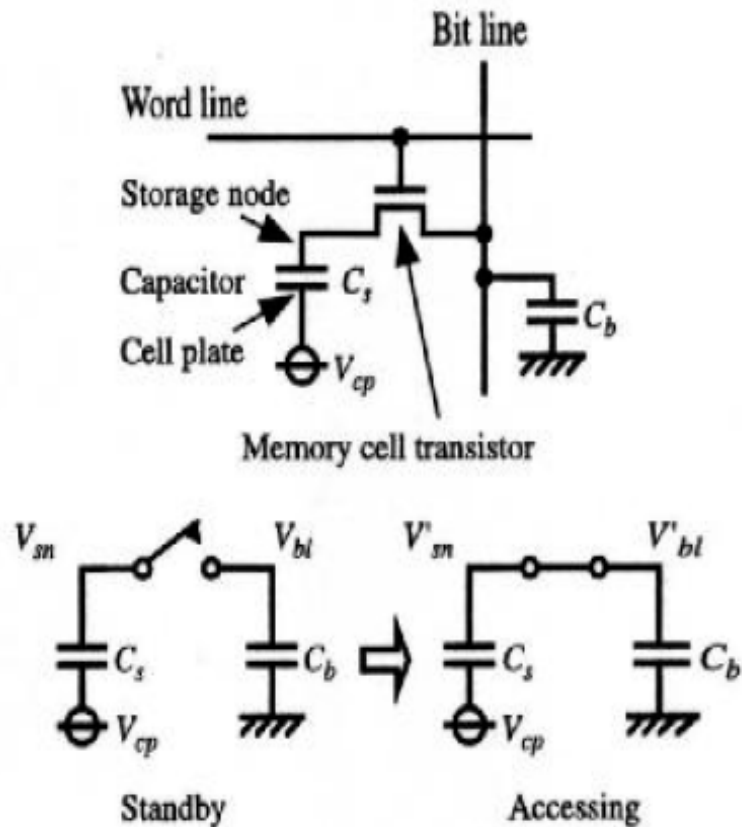
What does V_{Bit} become?

Does V_S change?



Why is this memory called “Dynamic”?

Bit-line voltage changes during READ



$$C_b = 300 \dots 600 \text{ fF}, C_s = 30 \text{ fF}$$

Written-State

$$Q = C_s (V_{sn} - V_{cp}) + C_b V_{bl}$$

$$\text{"1"} \quad V_{sn} = V_{ccs}$$

$$\text{"0"} \quad V_{sn} = 0$$

Precharge BL to $V_{bl} = V_{ccs} / 2$

Select WL with $V_{WL} > V_{ccs} + V_T^*$

$$Q = C_s (V'_{bl} - V_{cp}) + C_b \cdot V'_{bl}$$

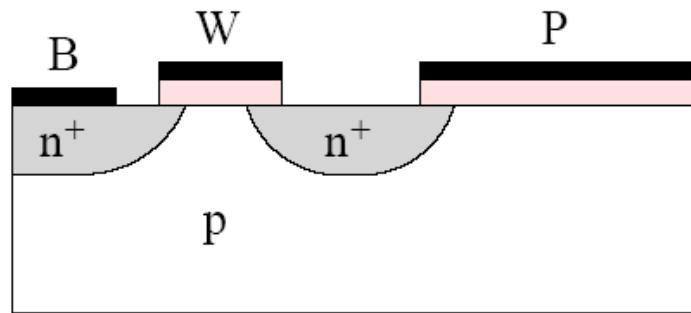
$$\Delta V = V'_{BL} - V_{BL} = (V_{SN} - V_{BL}) \frac{C_s}{C_s + C_b}$$

$$\Delta V_{\text{"1"}} = V'_{bl} - V_{bl} = \frac{1}{1 + C_b/C_s} \cdot \frac{V_{ccs}}{2}$$

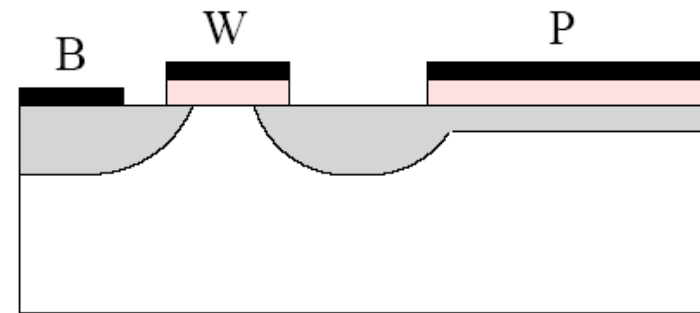
$$\Delta V_{\text{"0"}} = V'_{bl} - V_{bl} = -\frac{1}{1 + C_b/C_s} \cdot \frac{V_{ccs}}{2}$$

What's the point of V_{plate} ?

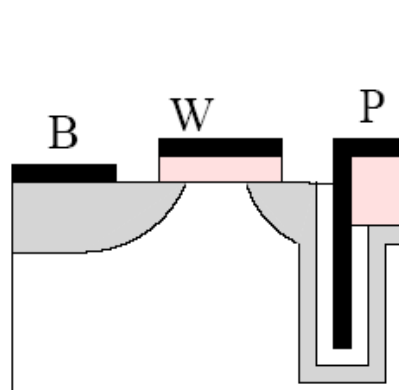
DRAM-capacitor evolution



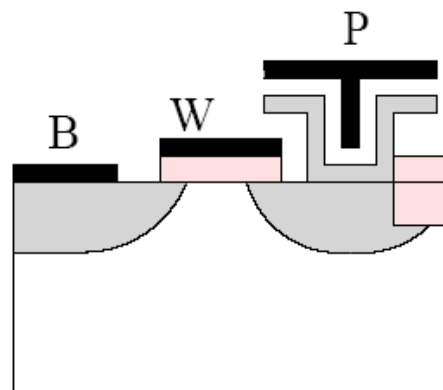
(a) MOS capacitor (4K)



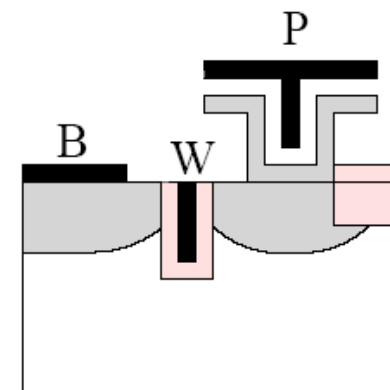
(b) Planar capacitor (64K - 1M)



(c) Trench capacitor
(1M - 1G)

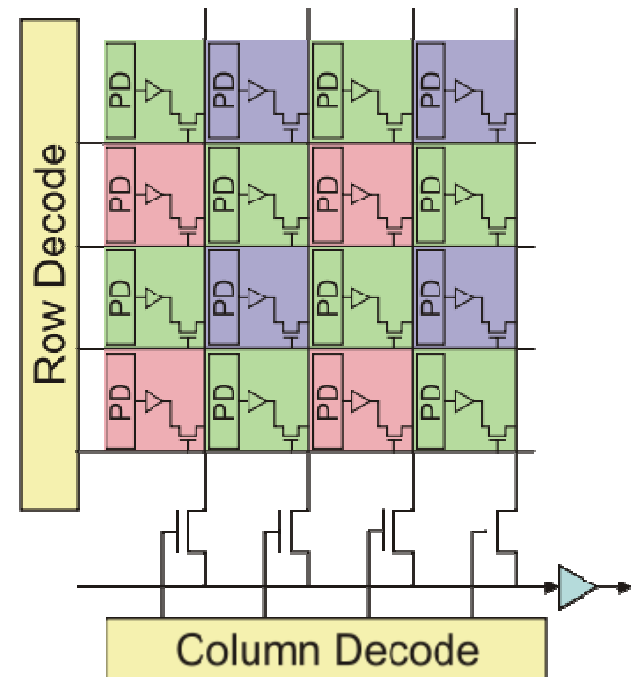
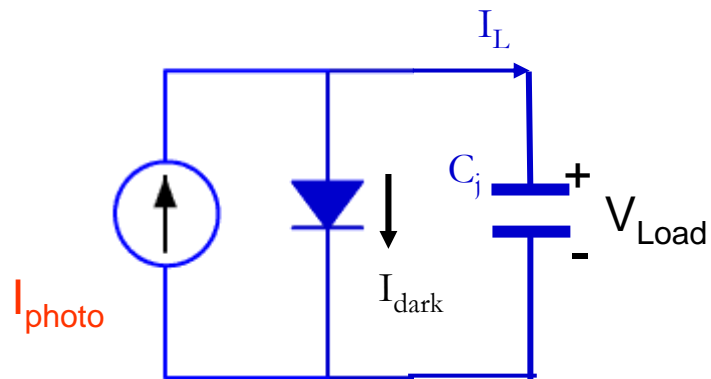
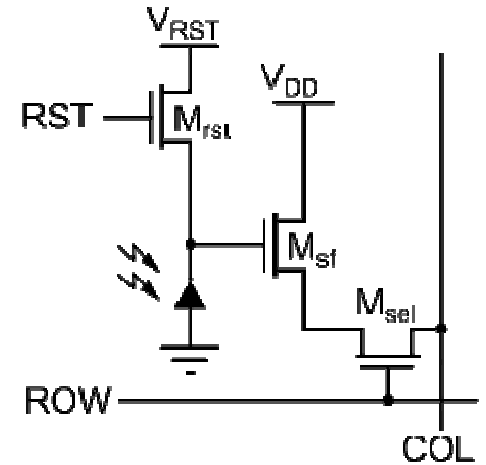
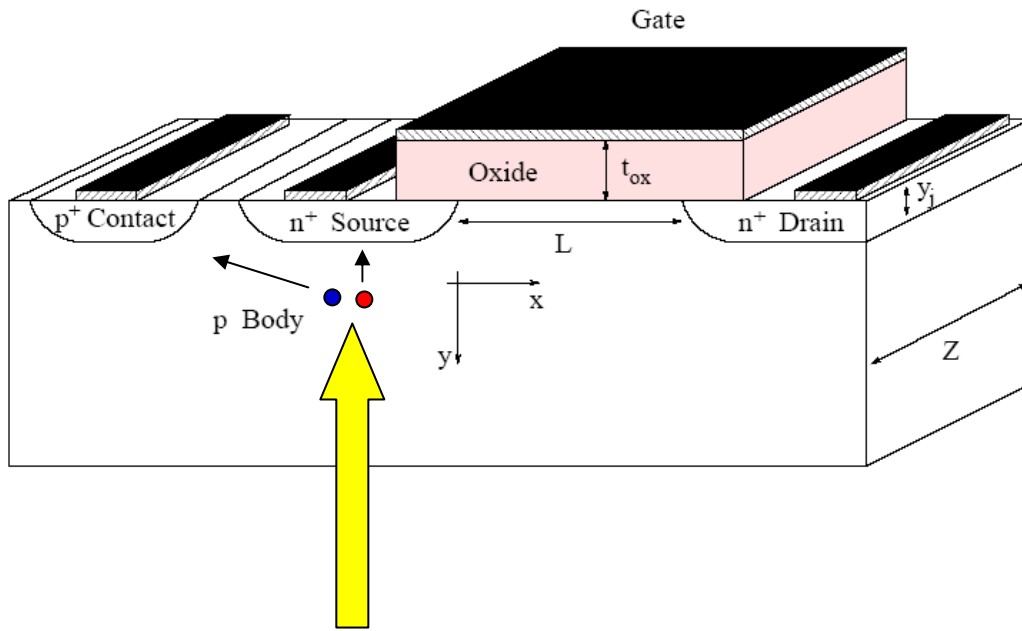


(d) Stacked capacitor
(4M -)



(e) Buried word line
(4G -)

CMOS camera



BJT Logic

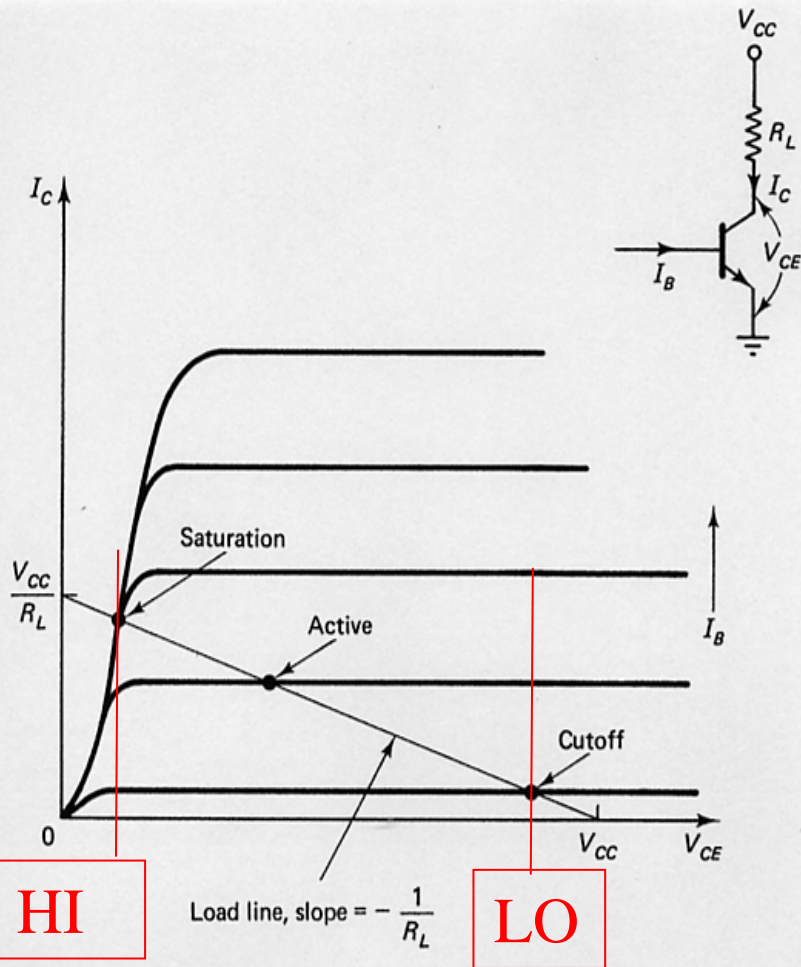
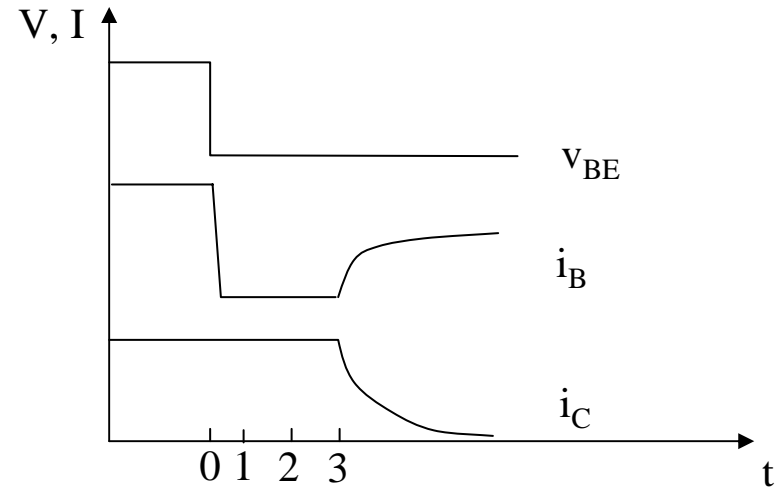
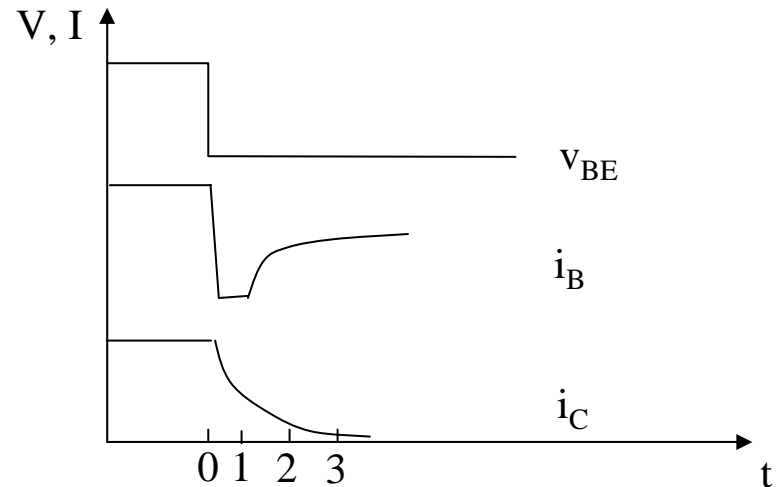


Figure 11E.7 Determination of the dc operating point by the superposition of transistor characteristics and the load line. Three such points, for different base currents, are shown.

Switching OFF from saturation:



Switching OFF from active:



BJT equivalent circuit (large signal)

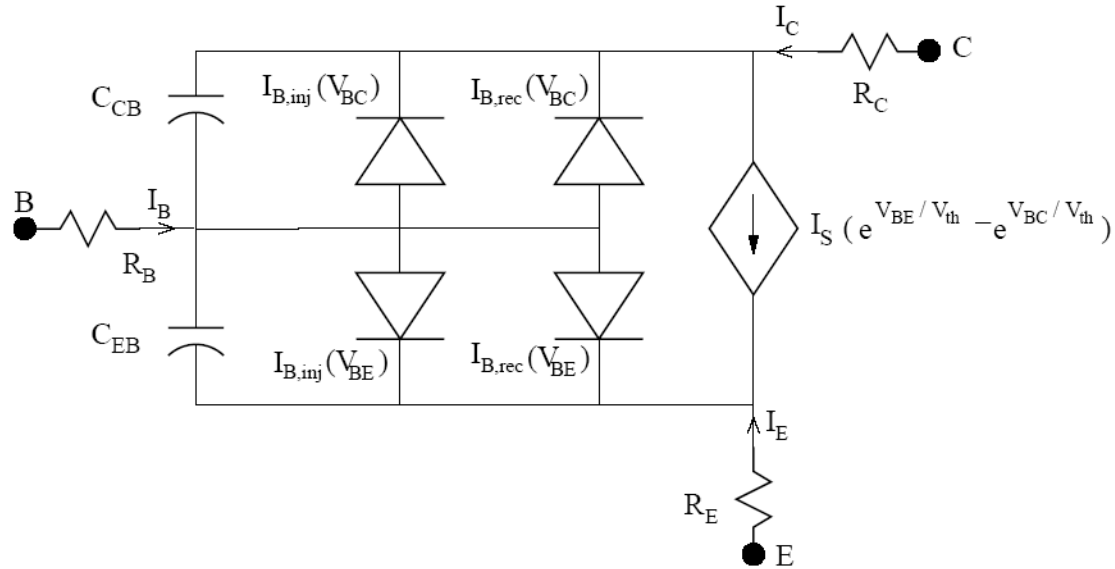
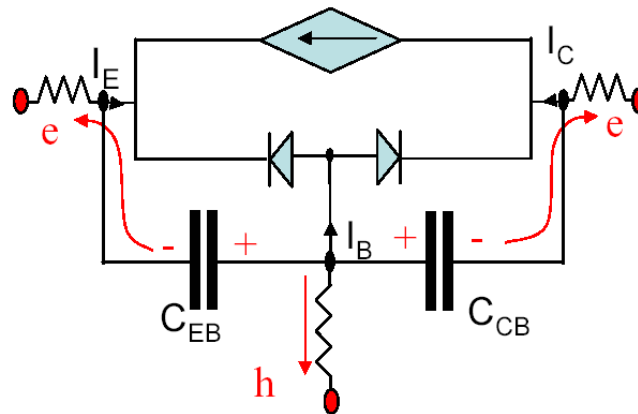
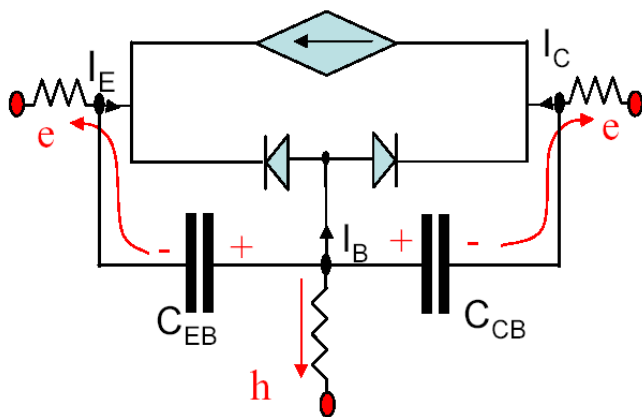
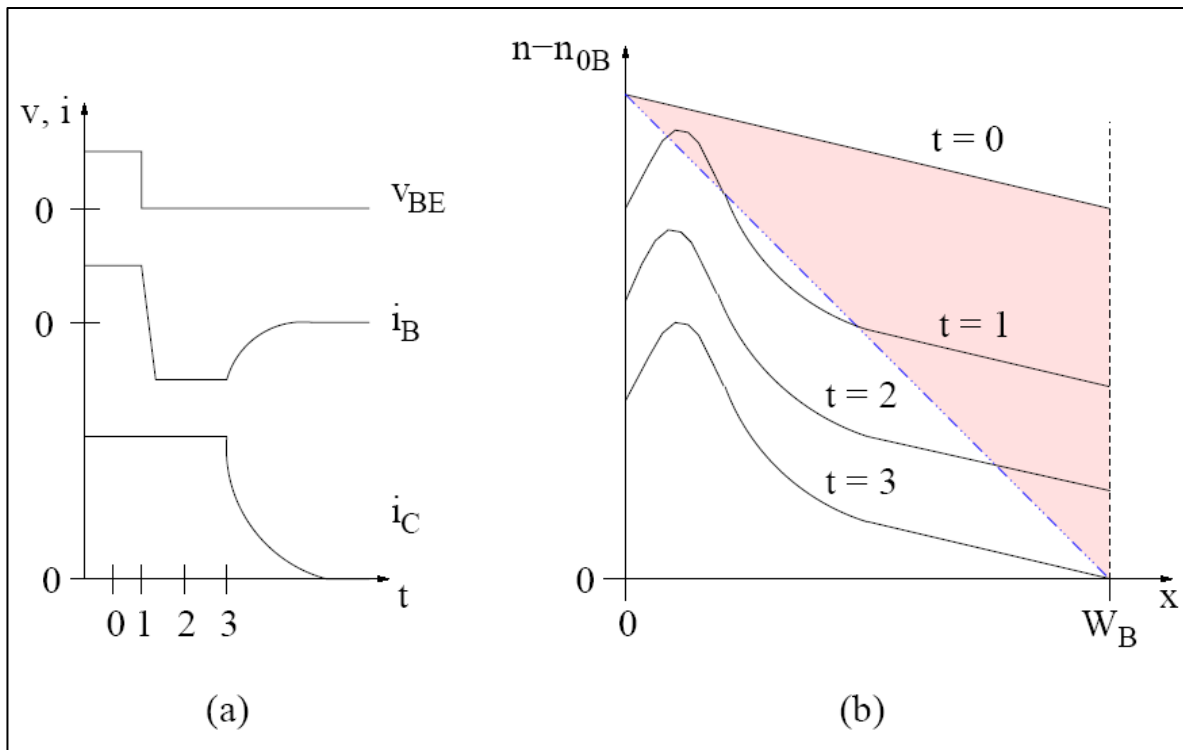


Figure 13.19 Large-signal equivalent circuit of the HBT. The collector current source is from Fig. 9.9.

Simplify and rotate

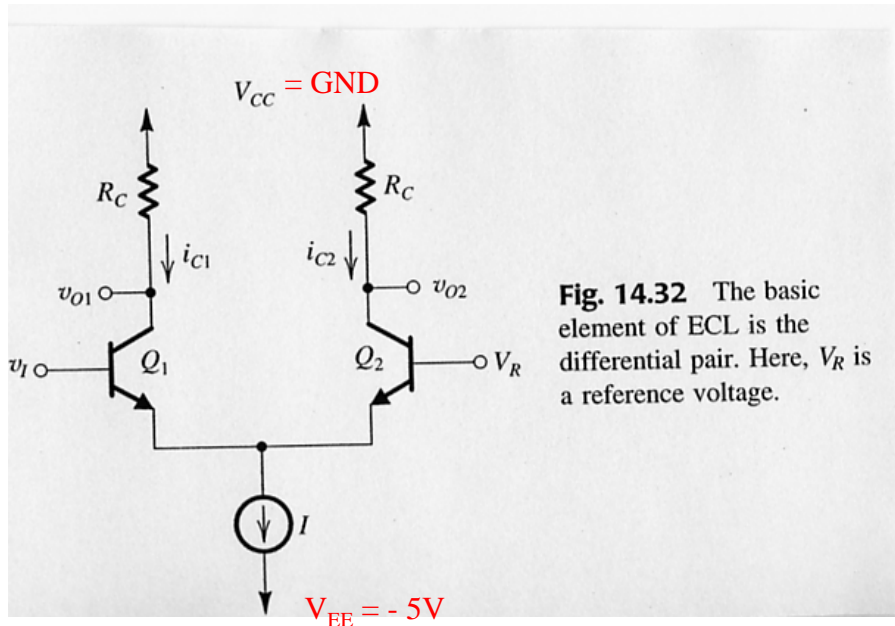


Why switching from saturation is slow

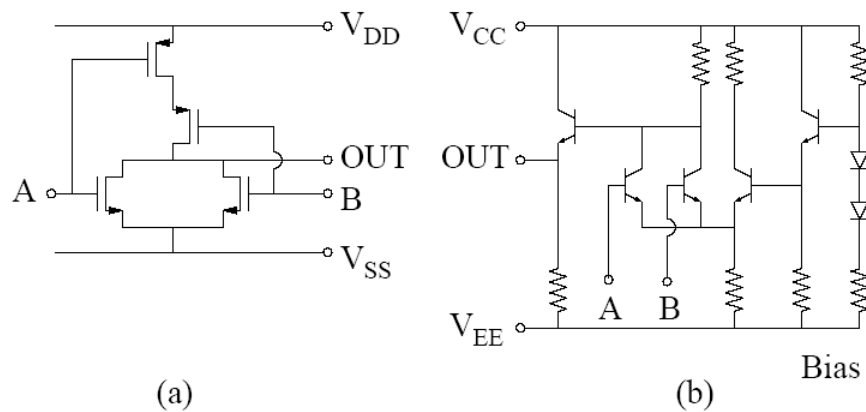


- Remove V_{BE}
- Depletion layers widen
- Holes flow OUT of base
- *i.e.*, I_B is reversed
- $n(0)$ and $n(W_B)$ decrease as V_j 's decrease
- But dn/dx stays same
- So I_C stays same
- Until $n(W_B) = n_0$

Basics of ECL, a non-saturating logic



- R 's and biases chosen so that Q 's never saturate.
- Differential logic, so only a small swing in v_i needed for switching.
- \therefore ECL is very fast.



What are the drawbacks?

Figure 13.2 Examples of 2-input NOR gates. (a) in CMOS, (b) in HBT emitter-coupled logic (ECL). The latter has a higher transistor count because, in addition to the actual emitter-coupled switching element, level shifters and a current source are required. However, it should also be noted that the ECL gate shown does allow complementary outputs.

Secs.
14.4-14.7

f_T and f_{\max} : HBT vs. MOS

$$2\pi f_T = \frac{g_m}{C_\pi + C_\mu(1 + g_m R_{ec})}$$

$$f_{\max} = \sqrt{\frac{f_{T,i}}{8\pi C_\mu R_b}}$$

What are the corresponding expressions for MOSFETs?

Which is “better”, HBT or MOSFET?